

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:	Charles W. Schietinger et al.		
Title:	Optical Techniques for Measuring Layer Thicknesses and Other Surface Characteristics of Objects Such as Semiconductor Wafers		
Application No.:	Unassigned	Filing Date:	Herewith
Examiner:	Unassigned	Group Art Unit:	Unassigned
Docket No.:	LUXT.118US2	Conf. No.:	Unassigned

Mail Stop Patent Application
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

PRELIMINARY AMENDMENT

Dear Sir:

Please amend the above-identified continuation application with which this Preliminary Amendment is being filed, as follows:

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of claims, which begins on page 3 of this paper.

Remarks begin on page 12 of this paper.

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Express Mail No.: EV321716457US